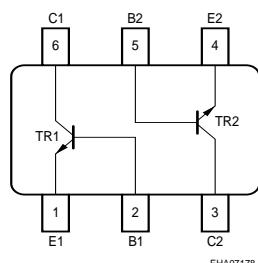
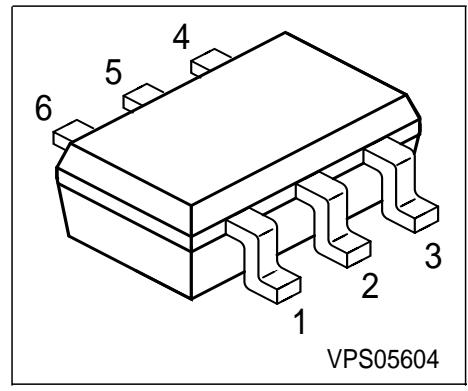


## NPN Silicon Switching Transistor Array

- High DC current gain: 0.1mA to 100mA
- Low collector-emitter saturation voltage
- Two ( galvanic) internal isolated Transistors with good matching in one package
- Complementary type: SMBT3906S (PNP)



Type	Marking	Pin Configuration						Package
SMBT3904S	s1A	1=E1	2=B1	3=C2	4=E2	5=B2	6=C1	SOT363

### Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CEO}$	40	V
Collector-base voltage	$V_{CBO}$	60	
Emitter-base voltage	$V_{EBO}$	6	
DC collector current	$I_C$	200	mA
Total power dissipation, $T_S = 115 \text{ }^\circ\text{C}$	$P_{tot}$	250	mW
Junction temperature	$T_j$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-65 ... 150	

### Thermal Resistance

Junction - soldering point <sup>1)</sup>	$R_{thJS}$	$\leq 140$	K/W
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<sup>1</sup>For calculation of  $R_{thJA}$  please refer to Application Note Thermal Resistance

**Electrical Characteristics** at  $T_A = 25^\circ\text{C}$ , unless otherwise specified.

<b>Parameter</b>	<b>Symbol</b>	<b>Values</b>			<b>Unit</b>
		<b>min.</b>	<b>typ.</b>	<b>max.</b>	
<b>DC Characteristics</b>					
Collector-emitter breakdown voltage $I_C = 1 \text{ mA}, I_B = 0$	$V_{(\text{BR})\text{CEO}}$	40	-	-	V
Collector-base breakdown voltage $I_C = 10 \mu\text{A}, I_E = 0$	$V_{(\text{BR})\text{CBO}}$	60	-	-	
Emitter-base breakdown voltage $I_E = 10 \mu\text{A}, I_C = 0$	$V_{(\text{BR})\text{EBO}}$	6	-	-	
Collector cutoff current $V_{CB} = 30 \text{ V}, I_E = 0$	$I_{\text{CBO}}$	-	-	50	nA
DC current gain 1) $I_C = 100 \mu\text{A}, V_{CE} = 1 \text{ V}$ $I_C = 1 \text{ mA}, V_{CE} = 1 \text{ V}$ $I_C = 10 \text{ mA}, V_{CE} = 1 \text{ V}$ $I_C = 50 \text{ mA}, V_{CE} = 1 \text{ V}$ $I_C = 100 \text{ mA}, V_{CE} = 1 \text{ V}$	$h_{FE}$	40 70 100 60 30	- - - - -	- - 300 - -	-
Collector-emitter saturation voltage1) $I_C = 10 \text{ mA}, I_B = 1 \text{ mA}$ $I_C = 50 \text{ mA}, I_B = 5 \text{ mA}$	$V_{\text{CEsat}}$	- -	- -	0.2 0.3	V
Base-emitter saturation voltage 1) $I_C = 10 \text{ mA}, I_B = 1 \text{ mA}$ $I_C = 50 \text{ mA}, I_B = 5 \text{ mA}$	$V_{\text{BEsat}}$	0.65 -	- -	0.85 0.95	

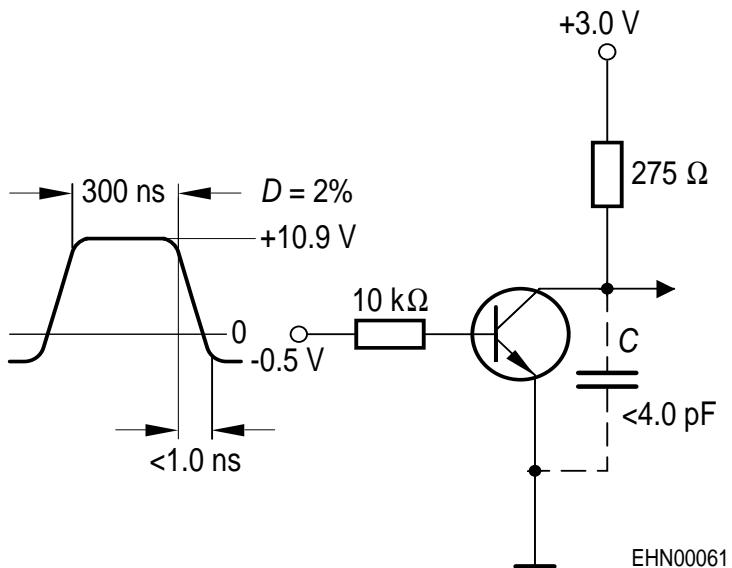
1) Pulse test:  $t < 300\mu\text{s}$ ;  $D < 2\%$

**Electrical Characteristics** at  $T_A = 25^\circ\text{C}$ , unless otherwise specified.

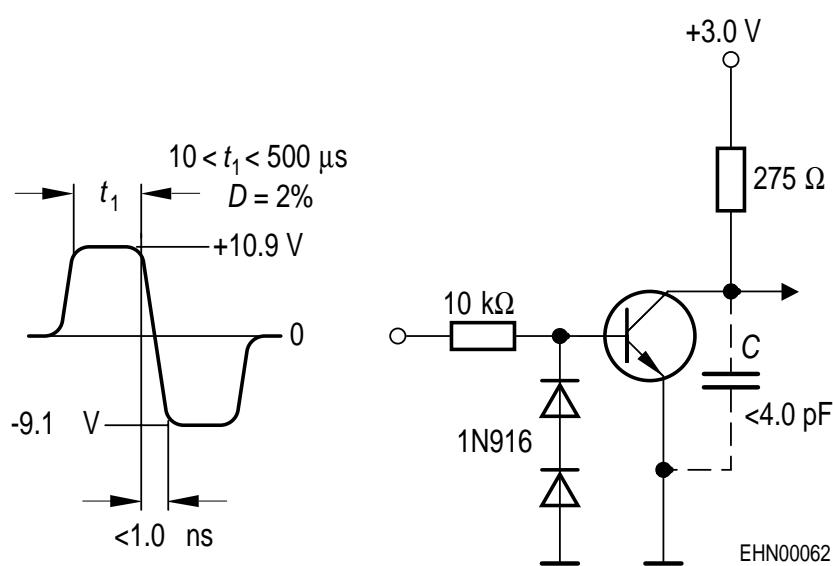
<b>Parameter</b>	<b>Symbol</b>	<b>Values</b>			<b>Unit</b>
		<b>min.</b>	<b>typ.</b>	<b>max.</b>	
<b>AC Characteristics</b>					
Transition frequency $I_C = 10 \text{ mA}, V_{CE} = 20 \text{ V}, f = 100 \text{ MHz}$	$f_T$	300	-	-	MHz
Collector-base capacitance $V_{CB} = 5 \text{ V}, f = 1 \text{ MHz}$	$C_{cb}$	-	-	4	pF
Emitter-base capacitance $V_{EB} = 0.5 \text{ V}, f = 1 \text{ MHz}$	$C_{eb}$	-	-	8	
Short-circuit input impedance $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{11e}$	1	-	10	k $\Omega$
Open-circuit reverse voltage transf.ratio $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{12e}$	0.5	-	8	$10^{-4}$
Short-circuit forward current transf.ratio $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{21e}$	100	-	400	-
Open-circuit output admittance $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{22e}$	1	-	40	$\mu\text{S}$
Noise figure $I_C = 100 \mu\text{A}, V_{CE} = 5 \text{ V}, R_S = 1 \text{ k}\Omega,$ $f = 1 \text{ kHz}, \Delta f = 200 \text{ Hz}$	$F$	-	-	5	dB
Delay time $V_{CC} = 3 \text{ V}, I_C = 10 \text{ mA}, I_{B1} = 1 \text{ mA},$ $V_{BE(\text{off})} = 0.5 \text{ V}$	$t_d$	-	-	35	ns
Rise time $V_{CC} = 3 \text{ V}, I_C = 10 \text{ mA}, I_{B1} = 1 \text{ mA},$ $V_{BE(\text{off})} = 0.5 \text{ V}$	$t_r$	-	-	35	
Storage time $V_{CC} = 3 \text{ V}, I_C = 10 \text{ mA}, I_{B1}=I_{B2} = 1\text{mA}$	$t_{stg}$	-	-	200	
Fall time $V_{CC} = 3 \text{ V}, I_C = 10 \text{ mA}, I_{B1}=I_{B2} = 1\text{mA}$	$t_f$	-	-	50	

## Test circuit

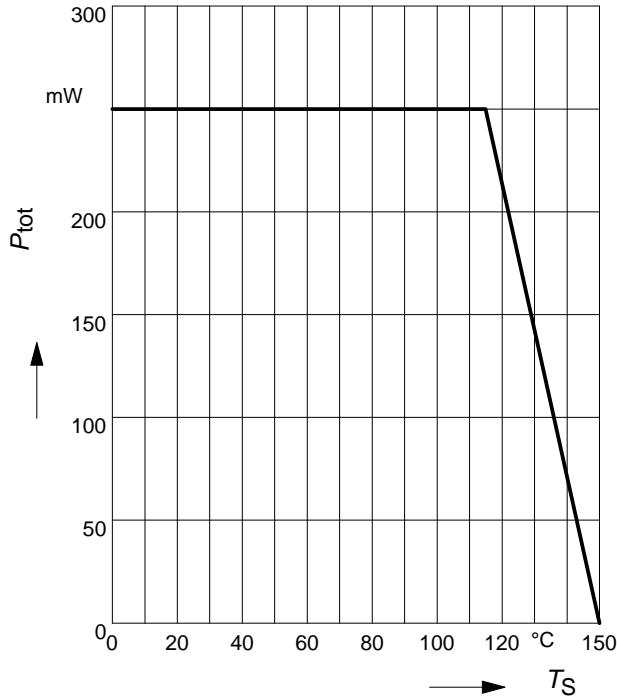
### Delay and rise time



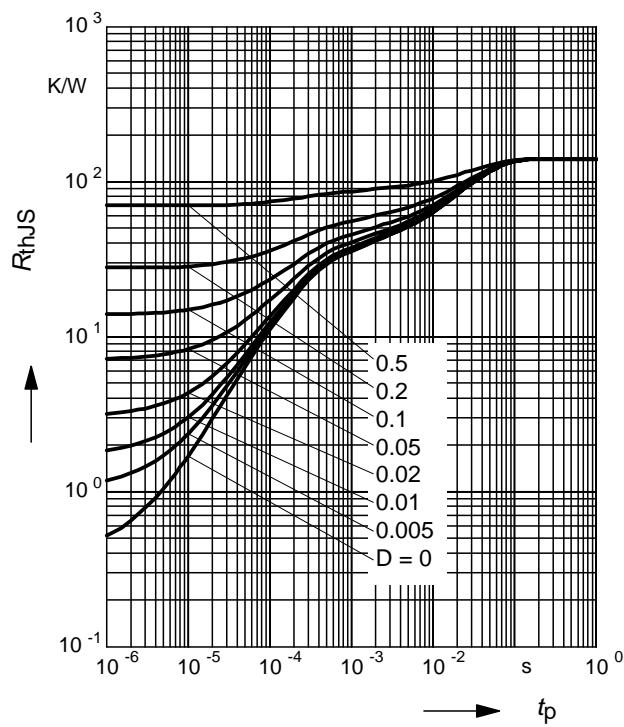
### Storage time and fall time



**Total power dissipation  $P_{\text{tot}} = f(T_S)$**

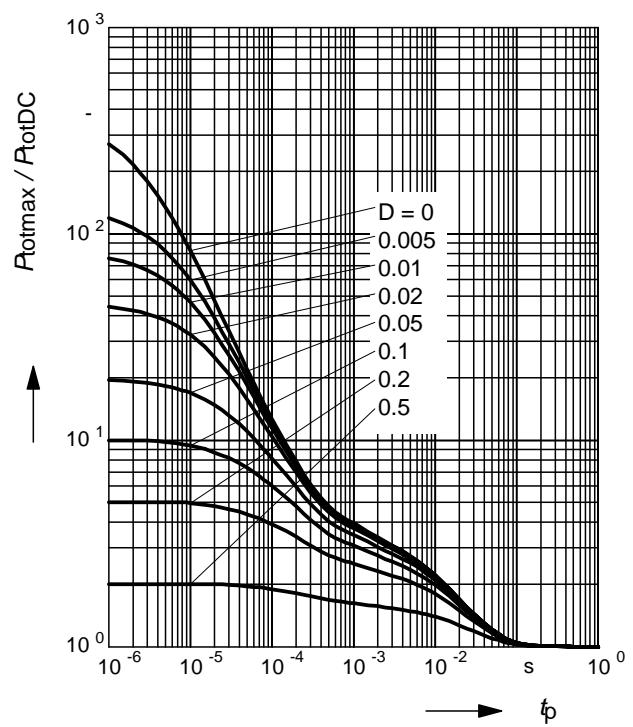


**Permissible Pulse Load  $R_{\text{thJS}} = f(t_p)$**



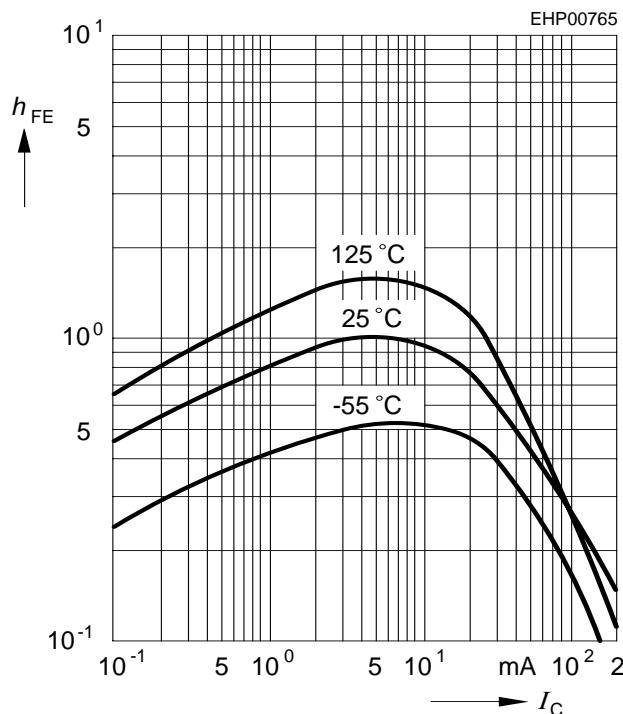
**Permissible Pulse Load**

$P_{\text{totmax}} / P_{\text{totDC}} = f(t_p)$



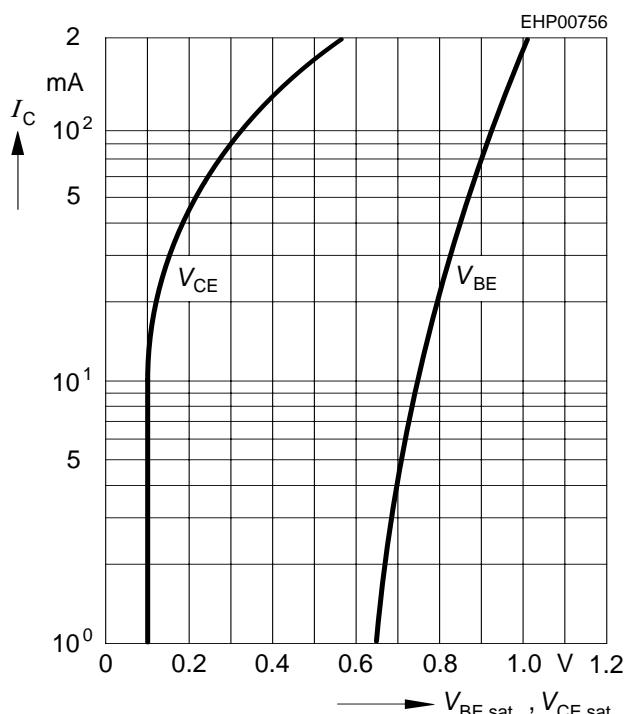
**DC current gain**  $h_{FE} = f(I_C)$

$V_{CE} = 10V$ , normalized



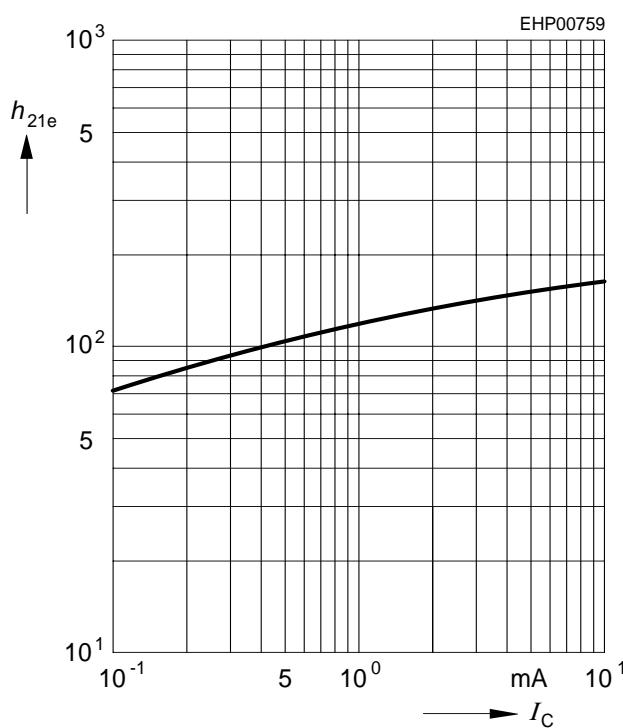
**Saturation voltage**  $I_C = f(V_{BEsat}, V_{CESat})$

$h_{FE} = 10$



**Short-circuit forward current transfer ratio**  $h_{21e} = f(I_C)$

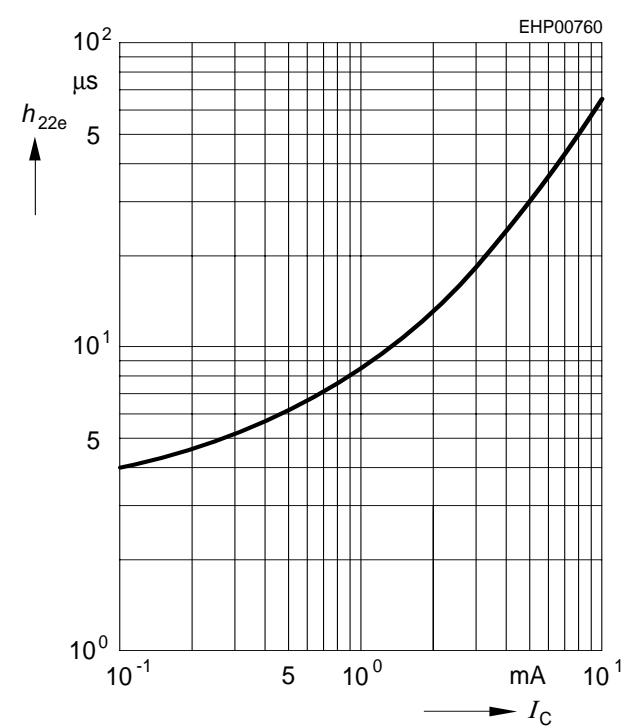
$V_{CE} = 10V, f = 1\text{MHz}$



**Open-circuit output admittance**

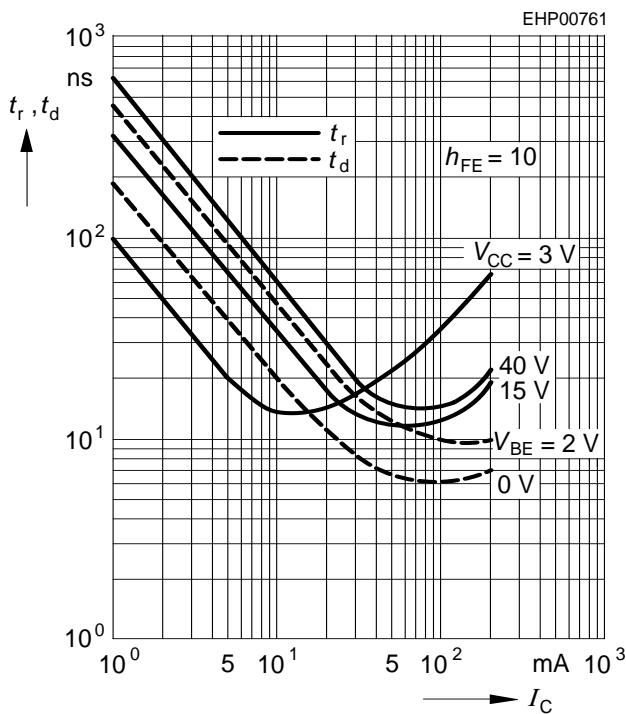
$h_{22e} = f(I_C)$

$V_{CE} = 10V, f = 1\text{MHz}$

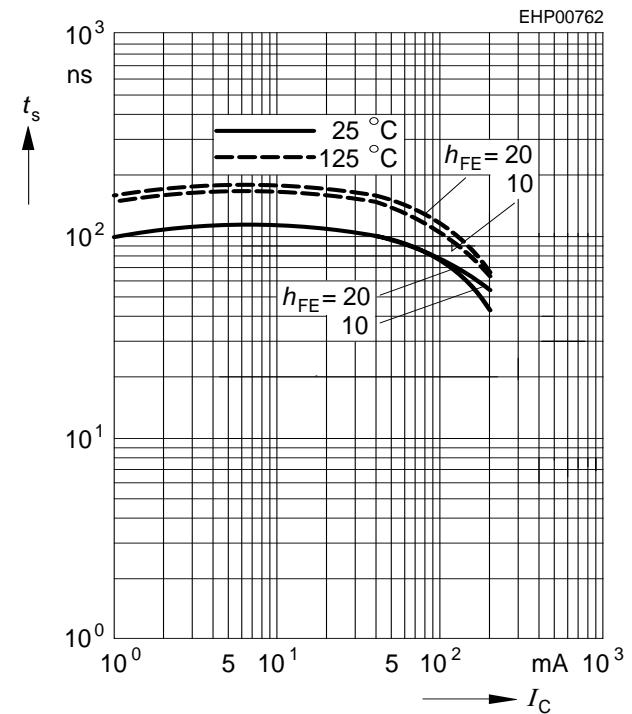


**Delay time**  $t_d = f(I_C)$

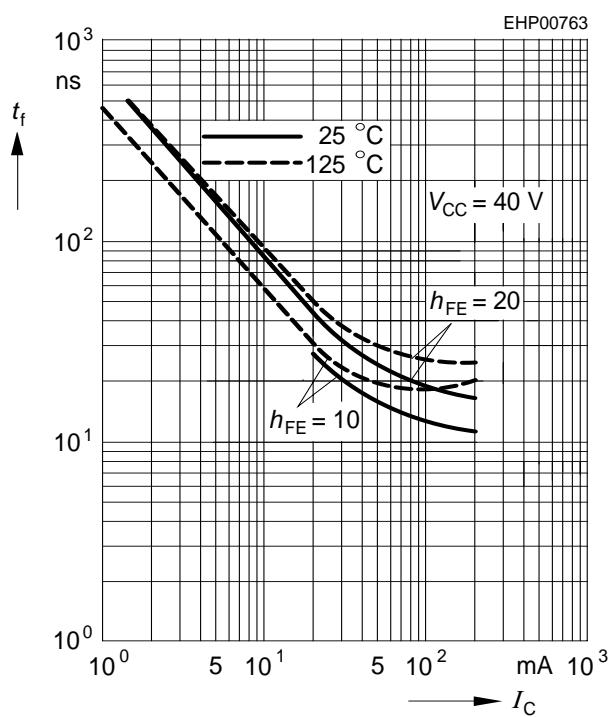
**Rise time**  $t_r = f(I_C)$



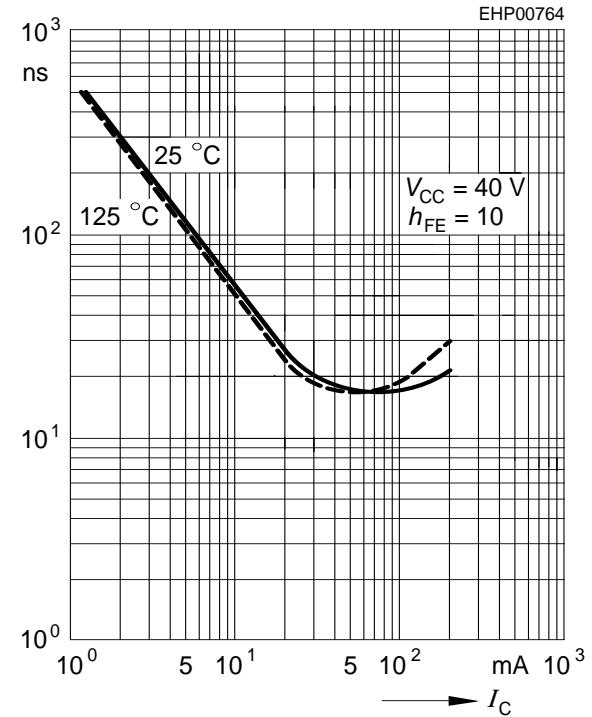
**Storage time**  $t_{stg} = f(I_C)$



**Fall time**  $t_f = f(I_C)$



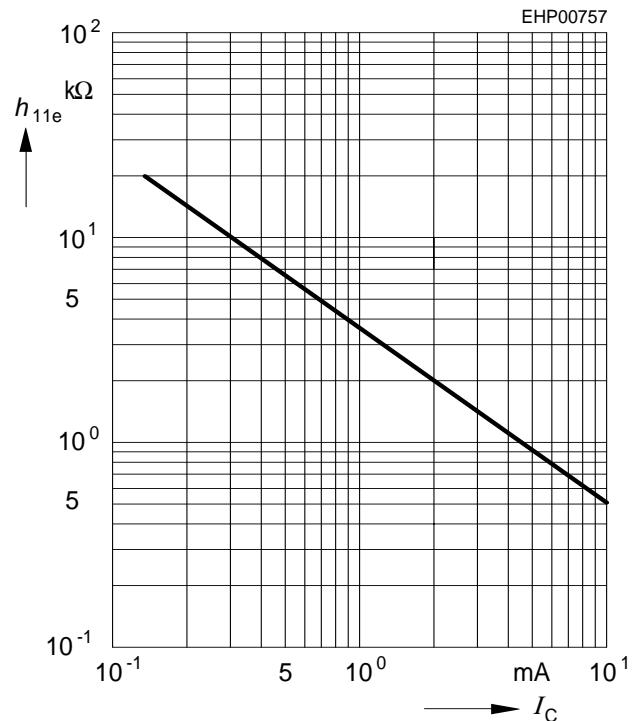
**Rise time**  $t_r = f(I_C)$



**Input impedance**

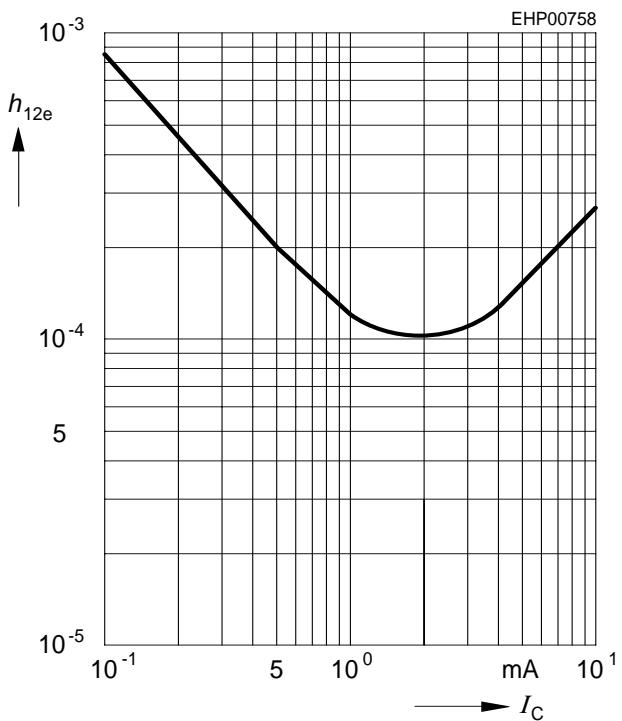
$$h_{11e} = f(I_C)$$

$V_{CE} = 10V, f = 1\text{kHz}$


**Open-circuit reverse voltage**

$$\text{transfer ratio } h_{12e} = f(I_C)$$

$V_{CE} = 10V, f = 1\text{kHz}$



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